Lecture 23: April 16

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23.1 Recap of non-parametric least squares

1. Wainwright's book Theorem 13.5: Suppose that the shifted function class $\mathcal{F}^* =$ $\{f - f^* : f \in \mathcal{F}\}\$ is star-shaped, and δ_n satisfies the critical inequality

$$
\frac{\mathcal{G}_n(\delta_n; \mathcal{F}^*)}{\delta_n} \le \frac{\delta_n}{2\sigma},
$$

then for any $t \geq \delta_n$, the nonparametric least-squares estimate \hat{f} satisfies the bound

$$
\mathbb{P}\left(\|\widehat{f} - f^*\|_n^2 \ge 16t\delta_n\right) \le e^{-\frac{n\delta_n}{2\sigma^2}}.
$$

The mean squared error is upper bounded by

$$
\mathbb{E} \|\widehat{f} - f^*\|_n^2 \lesssim \delta_n^2.
$$

- 2. Adaptivity: the rates can vary as a function of f^* , since the local Gaussian width $\mathcal{G}_n(\delta_n;\mathcal{F}^*)$ can vary as the true function f^* varies. Intuitively, if f^* is "simple", $\mathcal{G}_n(\delta_n; \mathcal{F}^*)$ can be small, and one would get a faster rate automatically.
- 3. Oracle inequality, Wainwright's book Theorem 13.13: Suppose that $\partial \mathcal{F} =$ ${f_1 - f_2 : f_1, f_2 \in \mathcal{F}}$ is star-shaped, and δ_n satisfies the critical inequality

$$
\frac{\mathcal{G}_n(\delta_n; \partial \mathcal{F})}{\delta_n} \leq \frac{\delta_n}{2\sigma},
$$

then for any $t \geq \delta_n$, the the nonparametric least-squares estimate \hat{f} satisfies the bound

$$
\|\widehat{f} - f^*\|_n^2 \le \inf_{\gamma \in (0,1)} \left\{ \frac{1+\gamma}{1-\gamma} \|f - f^*\|_n^2 + \frac{c_0}{\gamma(1-\gamma)} t \delta_n \right\} \quad \text{ for all } f \in \mathcal{F}
$$

with probability greater than $1 - c_1 e^{-c_2 \frac{n \delta_n}{\sigma^2}}$.

23.2 Minimax hypothesis testing

Given samples $X_1, \ldots, X_n \sim P$, consider the hypothesis testing:

$$
\text{null } H_0: P \in \mathcal{P}_0;
$$

alternative $H_1: P \in \mathcal{P}_1(\epsilon) = \mathcal{P}_1 \cap \{P : \rho(P, \mathcal{P}_0) \ge \epsilon\}.$

Define the test function as $\phi_T(X_1, \ldots, X_n) \in \{0,1\}$, where $\phi_T = 1$ means to reject the null and $\phi_T=0$ means to retain the null. Define the risk as

$$
R_{\epsilon}(T) = \underbrace{\sup_{P \in \mathcal{P}_0} \mathbb{E}[\phi_T]}_{\text{Type I error}} + \underbrace{\sup_{P \in \mathcal{P}_1(\epsilon)} \mathbb{E}[1 - \phi_T]}_{\text{Type II error}}.
$$

The minimax test is $\widehat{T} = \arg \min_{T} R_{\epsilon}(T)$.

We will define the critical radius to be some ϵ^* such that

$$
\inf_{T} R_{C_1 \epsilon^*}(T) \le 1/6,
$$

$$
\inf_{T} R_{C_2 \epsilon^*}(T) \ge 1/3.
$$

23.3 Gaussian mean testing

Consider $y = \theta^* + \eta$, where $\eta \sim N(0, \sigma^2 I_d)$. The two hypotheses are

$$
H_0: \theta^* = 0, \quad \mathcal{P}_0 = \{ N(0, \sigma^2 I_d) \};
$$

\n
$$
H_1: \|\theta^*\|_2 \ge \epsilon, \quad \mathcal{P}_1(\epsilon) = \{ N(\theta^*, \sigma^2 I_d) : \|\theta^*\|_2 \ge \epsilon \}.
$$

In the general case, we observe n samples y_1, \ldots, y_n and the critical radius scales as

$$
\epsilon^* \asymp \sigma \frac{d^{1/4}}{\sqrt{n}}.
$$

As a comparison, the minimax estimation rate is

$$
\epsilon^* \asymp \sigma \sqrt{\frac{d}{n}}.
$$

In general, it is often the case that minimax testing is a statistically easier problem than its estimation counterpart.

This problem is also related to two problems that you might come across in the minimax hypothesis testing literature.

- Our Gaussian mean testing problem is a special case of the problem of *signal detection*. Broadly, this is the problem of detecting the presence of a signal (generally, testing $\theta^* = 0$ against some class of alternatives).
- One can also view this as a multiple testing problem. Concretely, for each hypothesis $\{1,\ldots,d\}$ we can convert the y_i to a p-value (just use $\Phi(|y_i|)$, where $\Phi(\cdot)$ is the standard Gaussian CDF). Now, our mean testing problem is equivalent to the problem of global null testing. In that literature, one might study the minimax power against various types of alternatives (sparse, dense, . . .) and our setup roughly corresponds to testing against a possibly dense alternative.

In the remainder, we suppose that the sample size $n = 1$. One can replace σ by σ/\sqrt{n} in case of n samples.

23.3.1 Upper bound

Design the test statistics $T = \sum_{i=1}^d y_i^2$, and the test function $\phi_T = 1\{T \geq \mathbb{E}_0 T + C\sqrt{\text{Var}_0(T)}\}$.

Lemma 23.1 If $\mathbb{E}_1 T - \mathbb{E}_0 T \geq C(\sqrt{Var_0(T)} + \sqrt{Var_1(T)})$, then $R(T) \leq 2/C^2$.

Proof: Type I error is bounded by Chebshev's inequality as

$$
\mathbb{P}_0(T \ge \mathbb{E}_0 T + C\sqrt{\text{Var}_0(T)}) \le 1/C^2.
$$

Type II error is bounded similarly as

$$
\mathbb{P}_1(T \le \mathbb{E}_0 T + C\sqrt{\text{Var}_0(T)}) = \mathbb{P}_1(T - \mathbb{E}_1 T \le \mathbb{E}_0 T - \mathbb{E}_1 T + C\sqrt{\text{Var}_0(T)})
$$

$$
\le \mathbb{P}_1(T - \mathbb{E}_1 T \le -C\sqrt{\text{Var}_1(T)}) \le 1/C^2.
$$

Combine them to obtain

$$
R(T) = \sup_{P \in \mathcal{P}_0} \mathbb{E}[\phi_T] + \sup_{P \in \mathcal{P}_1(\epsilon)} \mathbb{E}[1 - \phi_T] \le 2/C^2.
$$

The means and variances are calculated as following:

- $\mathbb{E}_0 T = \sigma^2 d$.
- $\mathbb{E}_1 T = ||\theta^*||_2^2 + \sigma^2 d.$
- $Var_0(T) = \sum_{i=1}^d Var_0(y_i^2) = 2\sigma^4 d$, where

$$
Var_0(y_i^2) = \mathbb{E}[\eta_i^4] - (\mathbb{E}[\eta_i^2])^2 = 3\sigma^4 - \sigma^4 = 2\sigma^4.
$$

•
$$
\text{Var}_1(T) = \sum_{i=1}^d \text{Var}_1(y_i^2) = 4\sigma^2 \|\theta^*\|_2^2 + 2\sigma^4 d, \text{ where}
$$

$$
\text{Var}_1(y_i^2) = \text{Var}(\theta_i^{*2} + 2\theta_i^* \eta_i + \eta_i^2) = \text{Var}(2\theta_i^* \eta_i + \eta_i^2)
$$

$$
= \mathbb{E}[(2\theta_i^* \eta_i + \eta_i^2)^2] - (\mathbb{E}[2\theta_i^* \eta_i + \eta_i^2])^2
$$

$$
= \mathbb{E}[4\theta_i^{*2} \eta_i^2 + \eta_i^4] - \sigma^4
$$

$$
= 4\sigma^2 \theta_i^{*2} + 2\sigma^4.
$$

The condition $\mathbb{E}_1 T - \mathbb{E}_0 T \geq C(\sqrt{\text{Var}_0(T)} + \sqrt{\text{Var}_1(T)})$ is $\|\theta^*\|_2^2 \geq C(\sqrt{\text{Var}_0(T)} + \sqrt{\text{Var}_1(T)})$ √ $\sqrt{2\sigma^4 d} + \sqrt{2\sigma^4 d + 4\sigma^2 ||\theta^*||_2^2}.$ Therefore as long as $\|\theta^*\|_2 \gtrsim \sigma d^{1/4}$, the test will have a low risk $R(T) \leq 1/6$. This in turn proves our upper bound on the critical radius.

23.3.2 Lower bound

If we are testing a simple null against a simple alternative we know the optimal test, and we understand its Type I and Type II errors (by the Neyman-Pearson Lemma). To use this however one needs to transform the hypotheses into simple null v.s. simple alternative. Design the Bayesian counterpart as

$$
H_0: \theta^* = 0;
$$

$$
H_1: \theta^* \sim \epsilon S_{d-1},
$$

where \mathcal{S}_{d-1} denotes the d-dimensional unit sphere, and the parameter $\epsilon \approx \sigma d^{1/4}$.

Remark: It is crucial to introduce the spherical uniform sampling as the alternative hypothesis. It does not work if one uses a one-point alternative hypothesis

$$
H_0: \theta^* = 0;
$$

\n
$$
H_1: \theta^* = \epsilon(1/\sqrt{d}, \dots, 1/\sqrt{d}).
$$

In this case, the minimax test function is $\phi_T = 1\{\sum_{i=1}^d y_i \ge \epsilon\}$ √ $d/2$, and the minimax risk is

$$
R(T) = 2\mathbb{P}_0\left(\sum_{i=1}^d y_i \ge \frac{\epsilon}{2}\sqrt{d}\right) = 2\Phi\left(\frac{\epsilon}{2\sigma}\right),
$$

where $\Phi(\cdot)$ is the tail distribution function of the standard Gaussian distribution. In order to have a risk $R(T) \approx 1$, the parameter $\epsilon \approx \sigma$. The dimension d disappears, and the problem degenerates into a one-dimensional hypothesis testing problem.

To be continued...